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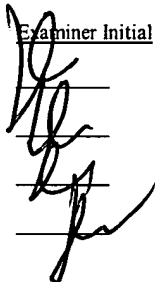
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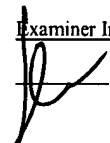
**INFORMATION DISCLOSURE CITATION**

Submitted May 25, 2002

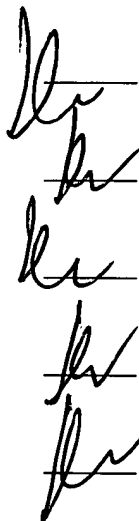
**U.S. Patent Documents**


<u>Examiner Initial</u>	<u>Document Number</u>	<u>Date</u>	<u>Name</u>
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**Foreign Patent Documents**


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**Other Documents**

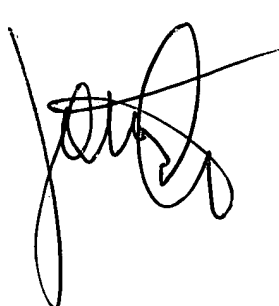
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